Form PTO 1449 (Modified)		U.S. DEPARTMENT PATENT AND TRA		ATTY DOCKET NO. 270265US0PCT		SERIAL NO. 10/532,247		
(моатеа)		PATENT AND TRA	DEWARK OFFICE					
APPLICANT APPLICANT								
LIST OF	KEFEF	RENCES CITED BY AF	PLICANT	Bernd BRUCHMANN, et al.				
				FILING DATE		GROUP		
				April 22, 2005		1711		
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIATE		
/T.T./	AA	2004/0016060 A1	01/29/2004	Jurgen DETERING, et al.				
/T.T./	AB	2004/0024087 A1	02/05/2004	Bernd BRUCHMANN,et al.				
/T.T./	AC	5,981,684	11/09/1999	Bernd BRUCHMANN,et al.				
/T.T./	AD	6,376,637 B1	04/23/2002	Bernd BRUCHMANN,et al.				
	ΑE							
	AF							
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	АН							
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	AJ							
	AK							
	AL							
	AM							
	AN							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES NO		
/T.T./	AO	WO 02/038851 A1	05/16/2002	WIPO (with English Abstract, corr. US 2004/0016060 A1)			×	
/T.T./	AP	WO 02/036697 A1	05/10/2002	WIPO (with English Abstract, corr. US 2004/0024087 A1)			×	
/T.T./	AQ	11-508630	07/27/1999	JAPAN (corr. US 5,981,684, corr. WO 97/02304 previously filed on 0	04/22/05)		×	
/T.T./	AR	7-504219	05/11/1995	JAPAN (corr. US 5,418,301 previously filed on 04/22/05)			X	
/T.T./	AS	2000-313732	11/14/2000	JAPAN (corr. US 6,376,637 B1, with corr. EP 1 026 185 A1)			×	
/T.T./	AT	1 026 185 A1	08/09/2000	EUROPE			X	
	AU							
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY							
	AZ				Add	itional Refe	erences sheet(s) attached	
Examiner /Thao Tran/ (05/12/2008)						Date Considered 05/12/2008		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in								
conformance and not considered. Include copy of this form with next communication to applicant.								